



深圳综合粒子设施研究院
Institute of Advanced Science Facilities, Shenzhen

The Design of Hard X-ray Spectroscopy Beamlines in Shenzhen Innovation Light source Facility (SILF)



Chunzhen Yang, Dr.
Environmental Science and Chemistry Group
Contact: yangcz@mail.iasf.ac.cn
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ray Beamline
高分辨硬X射线谱学线站

Synchrotron Radiation light sources



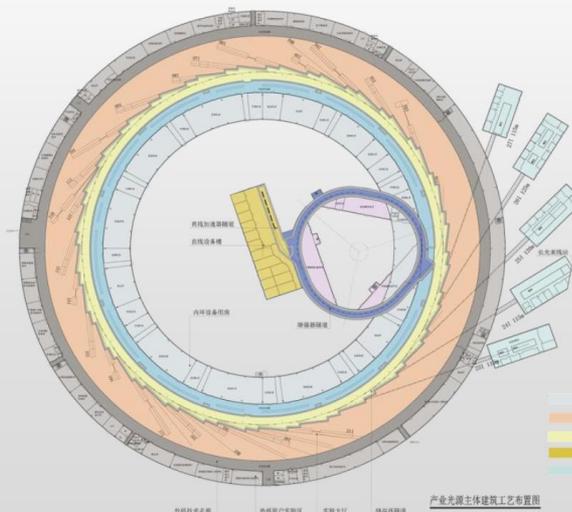


Guangming Science City

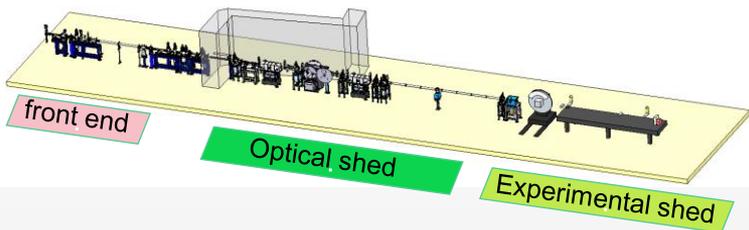


Hong Kong-Shenzhen Innovation and Technology Park

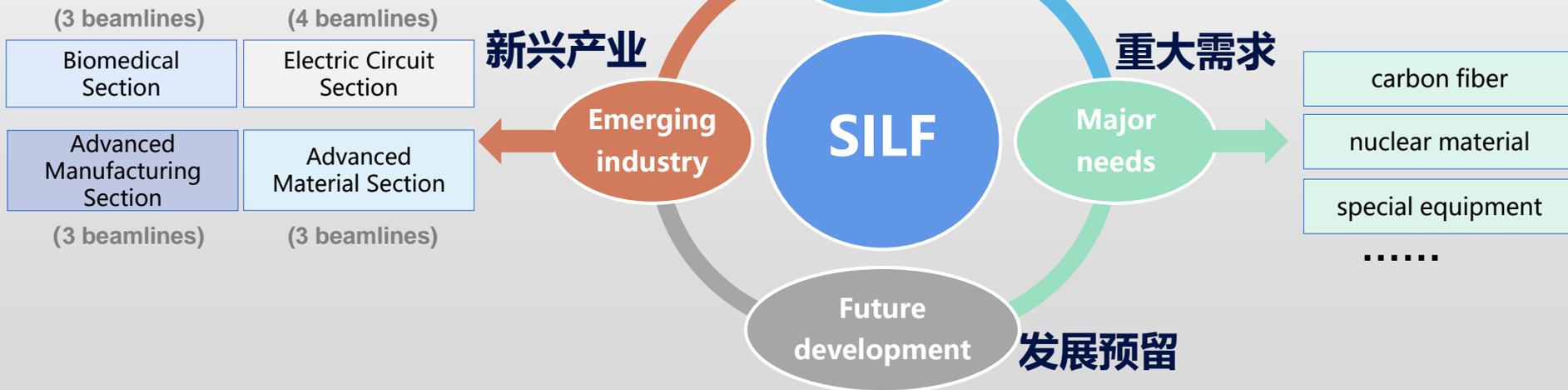
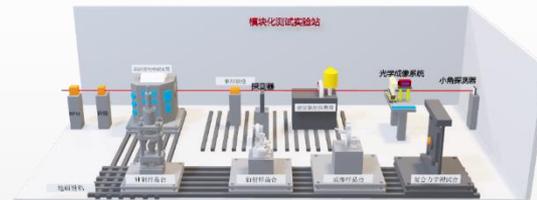
SILF is a fourth-generation diffraction-limited synchrotron radiation with an electron energy of **3 GeV** and low emittance of **<100 pm-rad**, and it provides photons with a broad range of energy from **4 meV to 160 keV**.



Parameter	Value
Energy/GeV	3.0
Circumference /m	700
Lattice type	7BA
Natural emittance / (pm-rad)	~100
Beam current/mA	200- 300



- marine resources
- Rare earth material
- Next generation semiconductor
- Green chemistry



Environmental Science and Chemistry Group

Beamlines	Front End	Energy (keV)	Mono-chromator	Key features	Experiments
1 X-ray coupled TEM Beamline X射线电子束联用线站	Wiggler	4.8 – 30	DCM	<ul style="list-style-type: none">✓ Time resolved QXAFS✓ Both high time resolution and high space resolution	<ul style="list-style-type: none">✓ XAFS✓ QXAFS✓ XAFS-TEM✓ TEM-EELS
2 Environmental Science Beamline 环境能源线站	IVU22	2.05 – 16	DCM	<ul style="list-style-type: none">✓ High detection limit✓ High space resolution✓ Element mapping image	<ul style="list-style-type: none">✓ μ-XRF✓ μ-XRD✓ μ-XANES
3 High Resolution Hard X-ray Beamline 高分辨硬X射线谱学线站	IVU24	4 – 20	DCM&HRM	<ul style="list-style-type: none">✓ High energy resolution for electronic structure analysis✓ 磁性材料测量	<ul style="list-style-type: none">✓ HERFD-XAS✓ RIXSXES/XRS✓ HAXPES

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ray Beamline
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X-ray coupled TEM Beamline

1. Key features

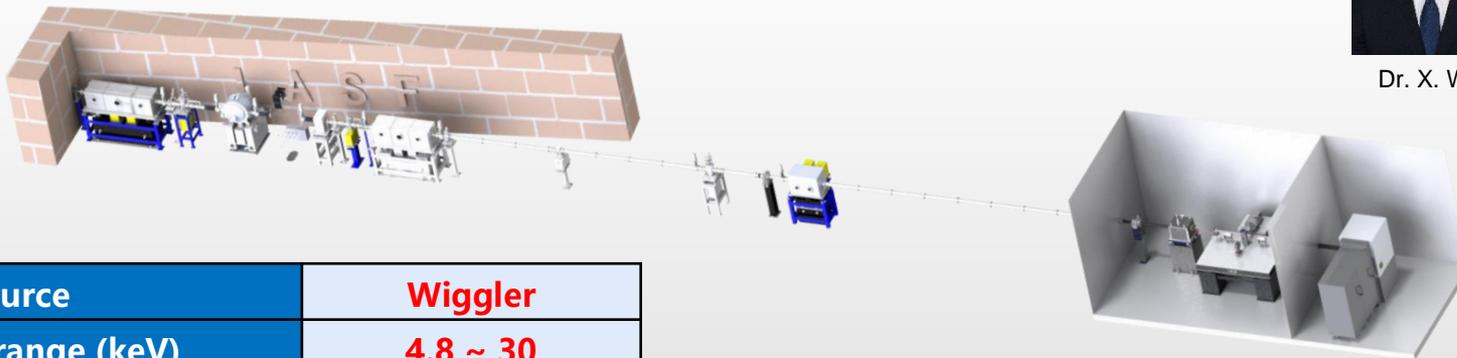
- ◆ Time-resolved XAFS
- ◆ X-ray coupled TEM analyses



Dr. X. Wang



Dr. M. Shu



Light source	Wiggler
Energy range (keV)	4.8 ~ 30
Energy resolution	$\sim 10^{-4}$
Flux at 10 keV (ph/s)	$10^{12} \sim 10^{13}$ ph/s
Spot size at sample (μm^2)	0.3×0.3 (EH1) 2×0.3 (EH2)
Key features:	100 ms

Methodology

XAFS-TEM

QXAFS

XAFS

EELS

Application Fields

Catalysis

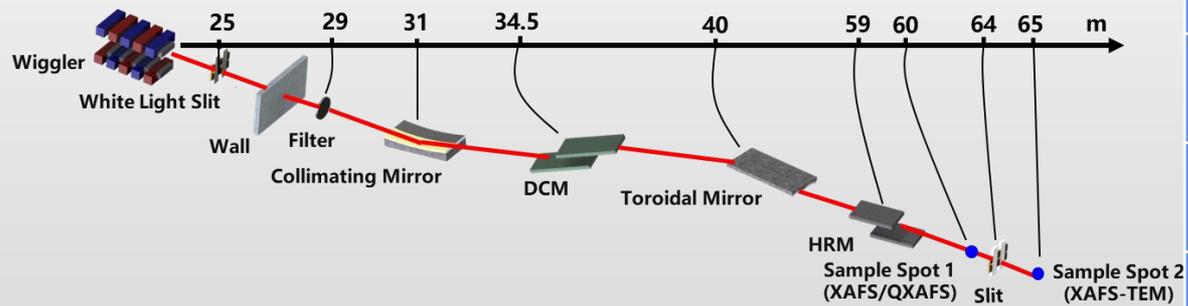
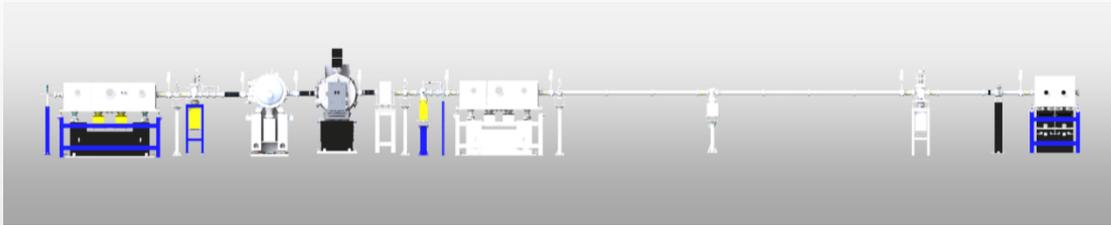
Battery

Environment

Archaeology

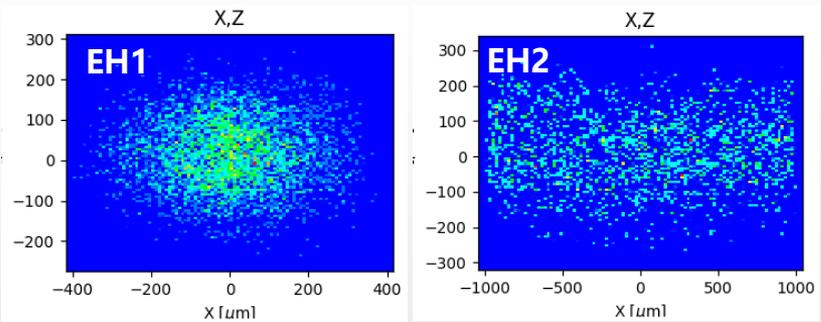
X-ray coupled TEM Beamline

2. Beamline Optics

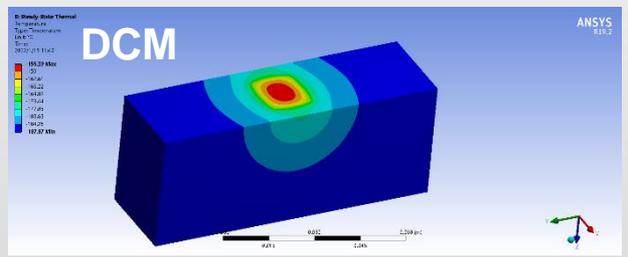
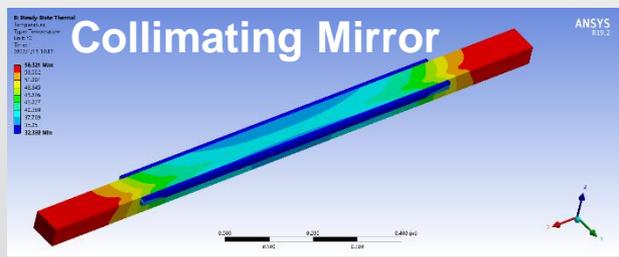
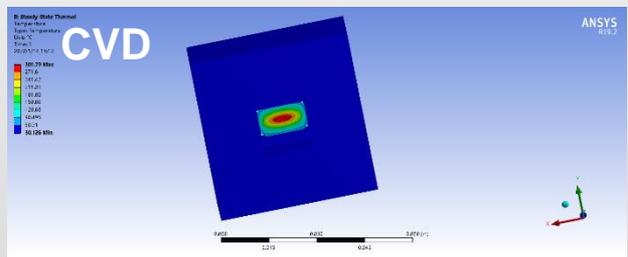


Source	Wiggler, 50 mm, 40 period, 1.9 T
Angle acceptance	500×100 (μrad, H×V)
Collimating Mirror	Rh, Pt
Monochromator	Si(111), Si(311)
Focusing Mirror	Rh, Pt
Harmonic Reject Mirror	Si, Rh, Pt

3. X-ray tracing and thermal analyses



Sample Spot	EH1	EH2
Position (m)	60	65
Energy (keV)	10	10
Size (μm^2 , FWHM, H×V)	216.55×193.40	1939.98×278.17
Divergence(μrad^2 , FWHM, H×V)	969.15×127.58	345.21×112.65
Flux (phs/s/0.1% bw)	1.56E+13 (10 keV)	6.00E+12 (10 keV)



OE	CVD	CM	DCM
Power (W)	158	304	551
Power Density (W/mm^2)	3.81	0.018	2.19

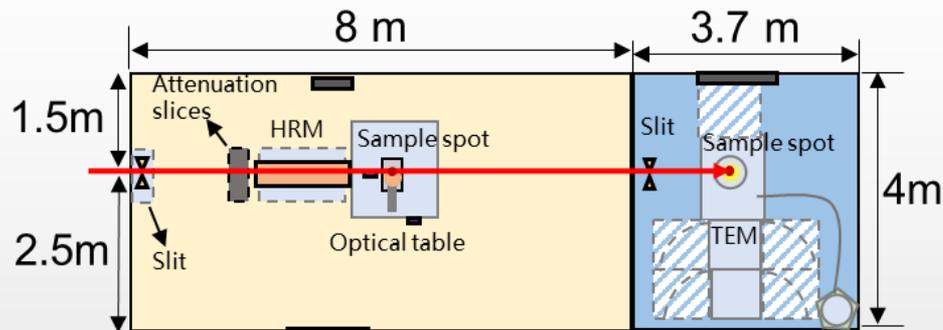
4. Experimental Hutch

EH 1: Universal XAFS hutch

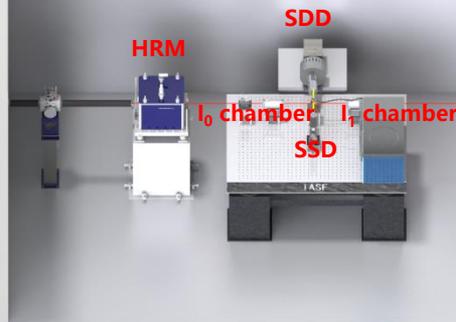
- ✓ Transmission XAFS
- ✓ Fluorescence XAFS
- ✓ Time solved XAFS

EH 2: TEM hutch

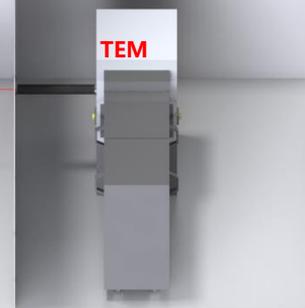
- ✓ XAFS-TEM
- ✓ HR-TEM
- ✓ EELS



Universal XAFS experimental station



XAFS-TEM experimental station



5. Detectors and Instruments



Channel-cut Monochromator



In-situ XAFS



Ionization chamber



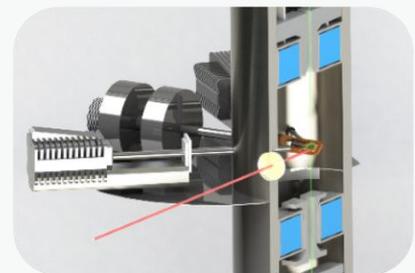
Lytle chamber



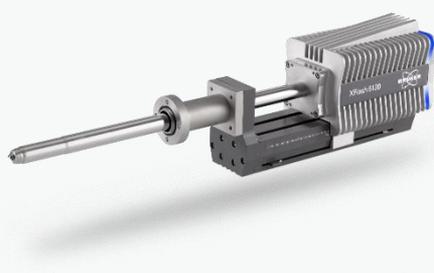
Solid state detector



TEM



XAFS-TEM



Silicon drift detector



Sample holder

6. User Facilities

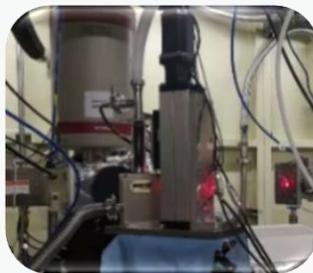
X-ray coupled TEM Beamline was equipped with **universal XAFS** and **TEM** test, and a diversity of **in situ XAFS devices** for catalytical reaction, battery property test, and combined test by XAFS-TEM.



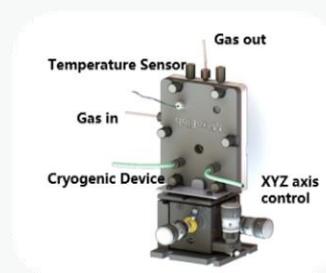
Multi-environmental test



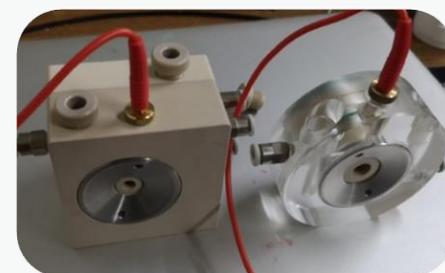
Thermo catalytic operando cell



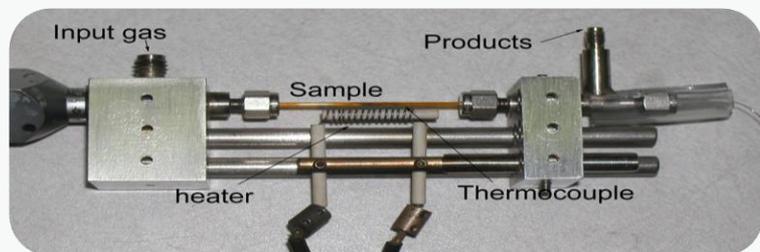
In situ cryogenic device



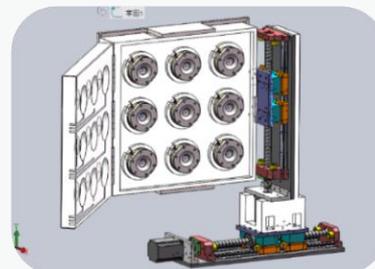
In situ battery cell



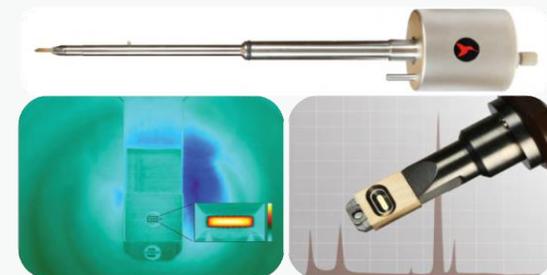
In situ electrochemical cell



Thermo catalytic cell



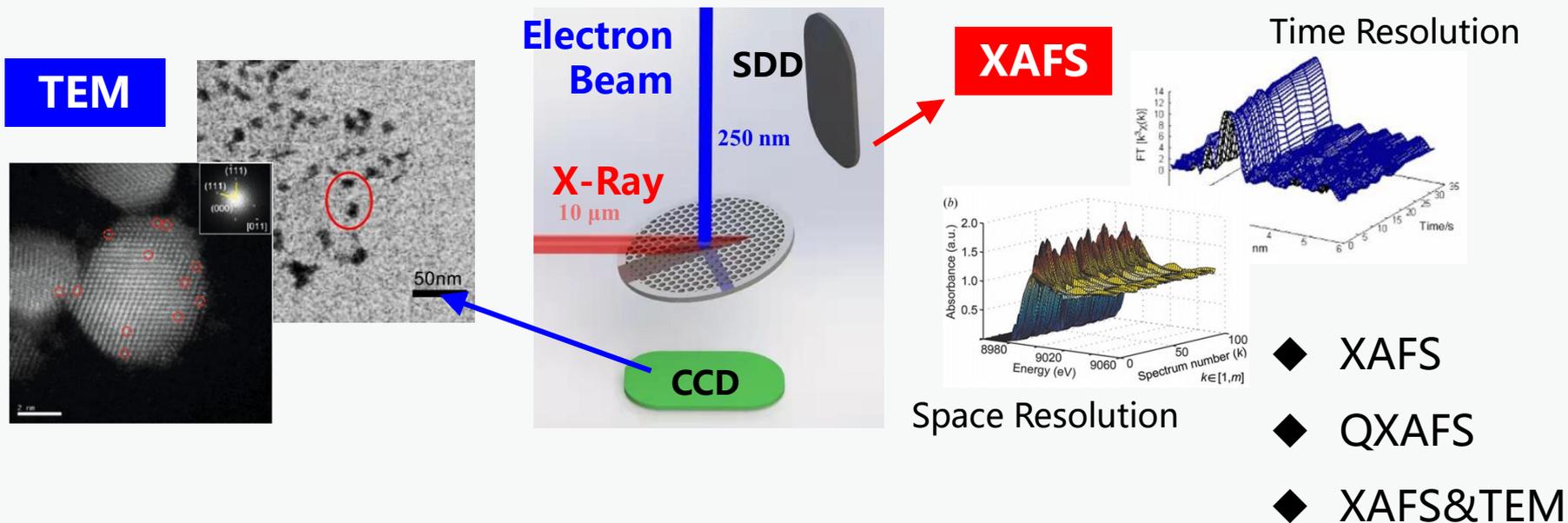
Automated in-situ XAFS battery test system



In-situ sample holder

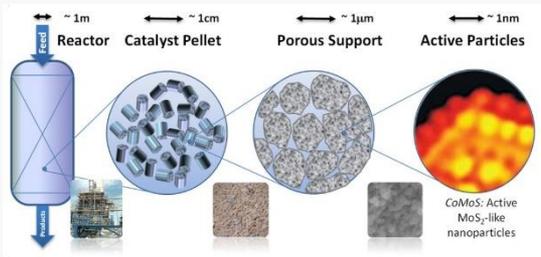
7. Unique features

- Obtain the microscopy morphology, element distribution and the valence state, local coordination structure of samples at the same time

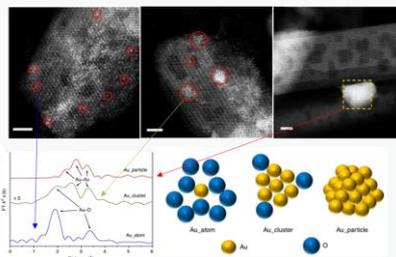


8. Potential applications

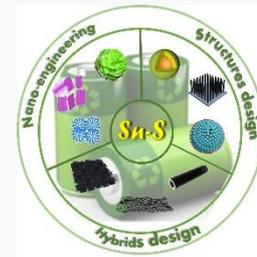
- Focus on the structure and chemical properties of catalysis, material science, electrode material, etc., in order to understand and design better materials



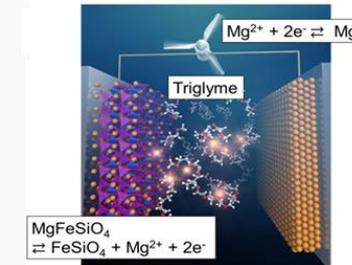
Morphology of industrial catalysts



Relationship of structure & activity

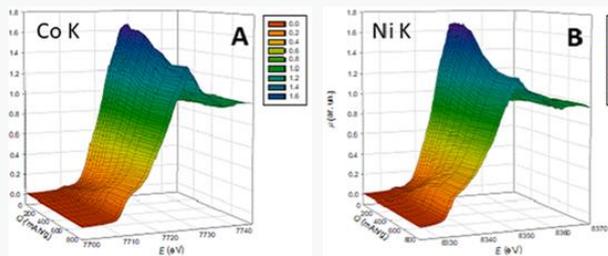


Li-ion battery

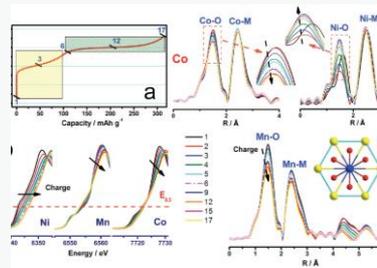


fuel cell

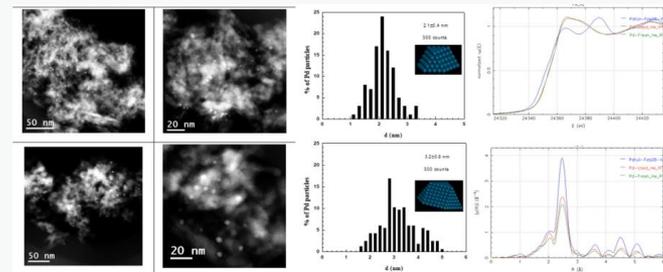
- Understanding the affection of environment (temperature, pressure, voltage, charge time, etc.) to control a better operated conditions



XAFS for electron chemistry



XAFS for supercharge



XAFS-TEM for catalysts

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High Resolution Hard X-
ray Beamline
高分辨硬X射线谱学线站

1. Key features

- ◆ high spatial resolution
- ◆ ultra-sensitive element detection



Dr. M. WANG



Dr. X. LIN

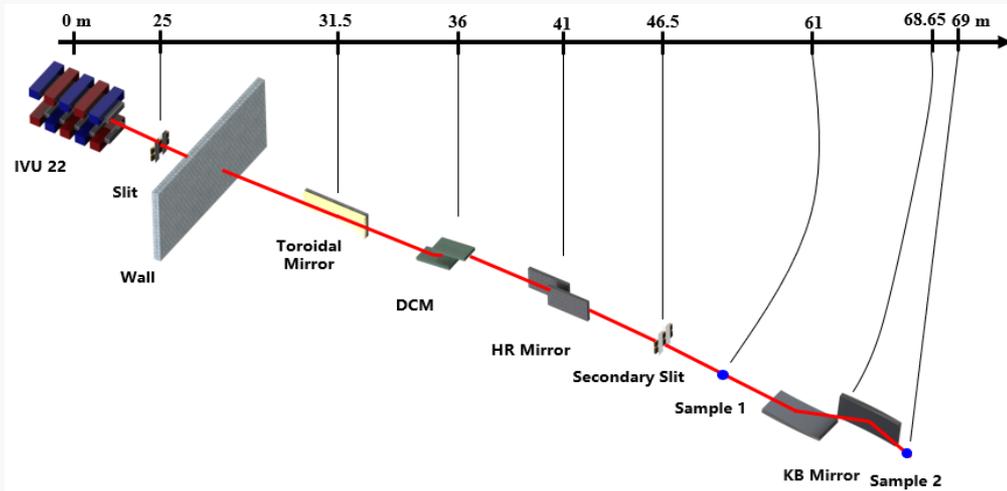
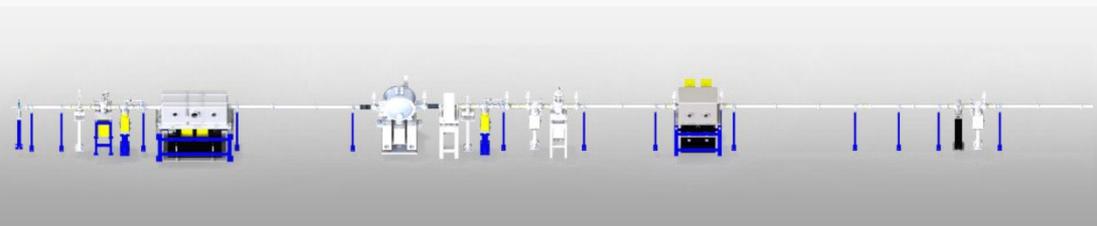


Light source	Undulator
Energy range (keV)	2.05 ~ 16
Energy resolution	$\sim 10^{-4}$
Flux at 2.5 keV (ph/s)	10^{12} ph/s
Spot size at sample (μm^2)	$\sim 600 \times 600$ (EH1) $\sim 0.5 \times 0.5$ (EH2)
Key features	Space resolution: $< 0.5 \mu\text{m}$ Detection limit: ppb Cryogenic system: 10 k

Method
μ -XRF, XRF, TXRF, XFCT
μ -XANES, XANES
μ -EXAFS, EXAFS
μ -XRD, XRD

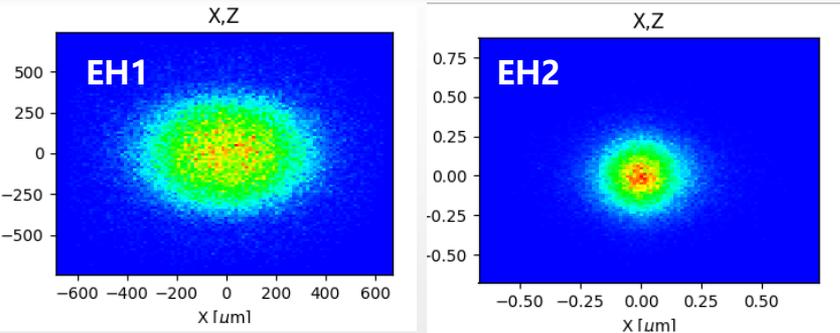
Applications
Environmental science
Energy materials
Life sciences
Geological science

2. Beamline Optics

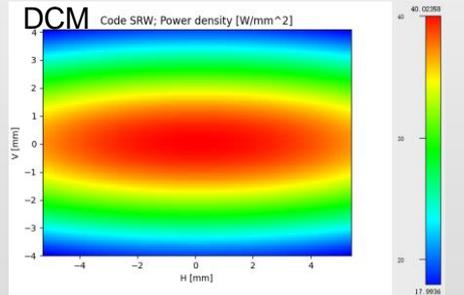
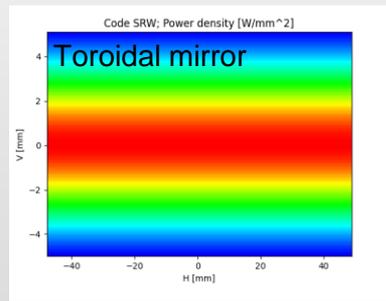
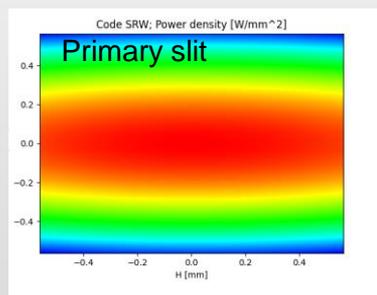


Source	IVU22, $\lambda=22\text{mm}$, $B_{\text{max}}=1.04\text{T}$, $\text{Gap}_{\text{min}}=5\text{ mm}$, $L=4.5\text{m}$
Angle acceptance (μrad)	$45 \times 45(\text{H} \times \text{V})$
Toroidal Mirror	Rh 3mrad Vertical collimation Horizontal focus
Monochromator	Si(111), Si(311)
KB Mirror	Rh 4mrad
Harmonic Reject Mirror	Cr(2.05~3.5 keV), Ni(3.0~35.5 keV), Rh(9~15 keV),

3. X-ray tracing and thermal analyses



Sample Spot	EH1	EH2
Position (m)	60	69
Energy (keV)	2.5	2.5
Size (μm^2 , FWHM, H×V)	462.30×475.9	0.23×0.31
Divergence(μrad^2 , FWHM, H×V)	35.33×0.63	2258.74×1122.12
Flux (phs/s/0.1% bw)	2.70E+13 (2.5 keV)	4.67E+12 (2.5 keV)

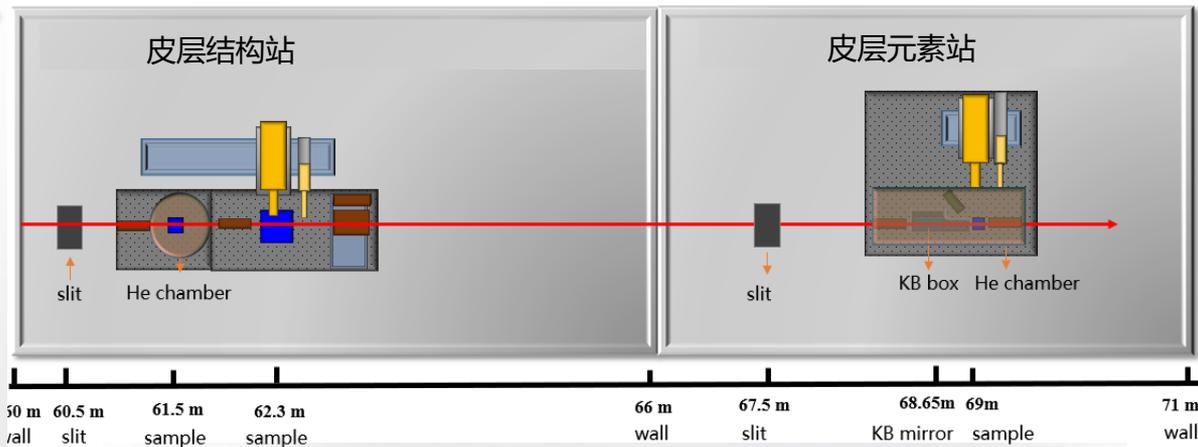


OE	Primary slit	Toroidal Mirror	DCM
Absorbed Power (W)	2473	18	70.27
Power Density (W/mm^2)	88.19	0.17	40.02

4. Experimental Hutch

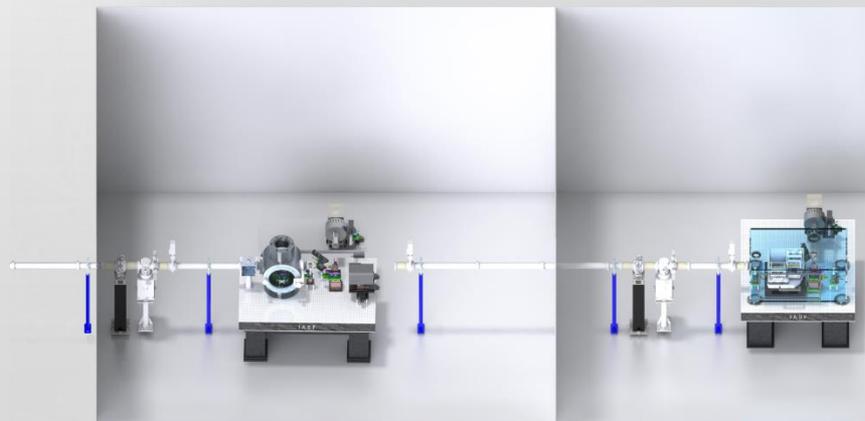
EH 1: micro spot size

- ✓ XRF
- ✓ TXRF
- ✓ confocal-XRF
- ✓ XFCT
- ✓ XRD
- ✓ XAFS



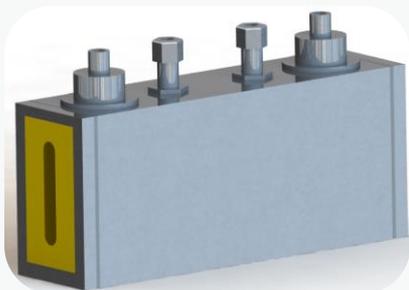
EH 2: sub-micro spot size

- ✓ μ -XRF
- ✓ μ -TXRF
- ✓ μ -XFCT
- ✓ μ -XAFS

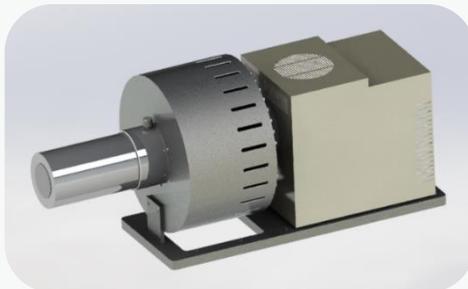


5. Detectors and Instruments

ion-chamber



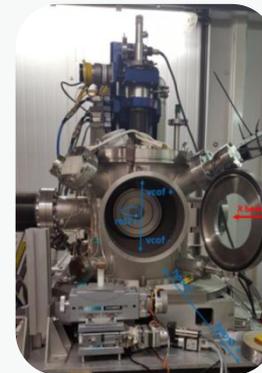
36 elements Ge SSD



Polycapillary optics



He/N₂/vacuum chamber



Eiger XRD detector



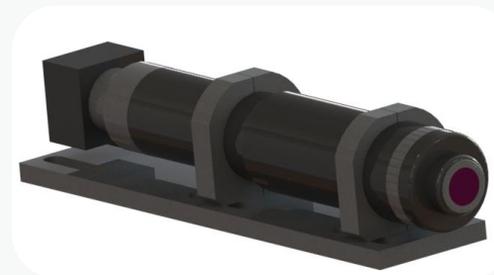
7 elements SDD



7D high precision sample stage



Optical camera

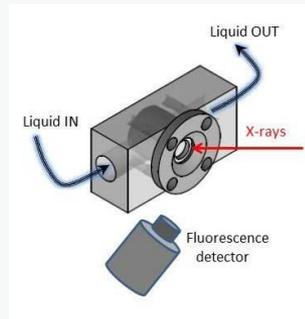


6. User Facilities

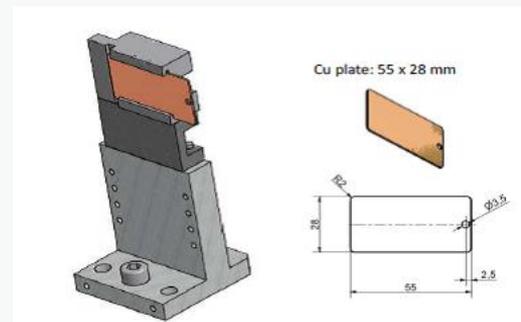
LHe/LN₂ cryostat



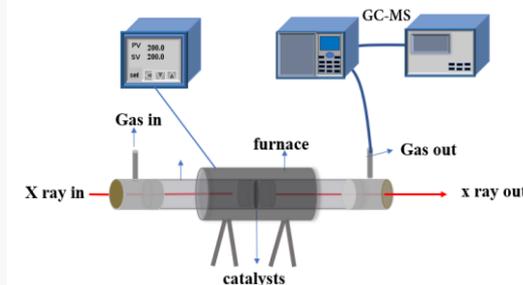
Liquid cell



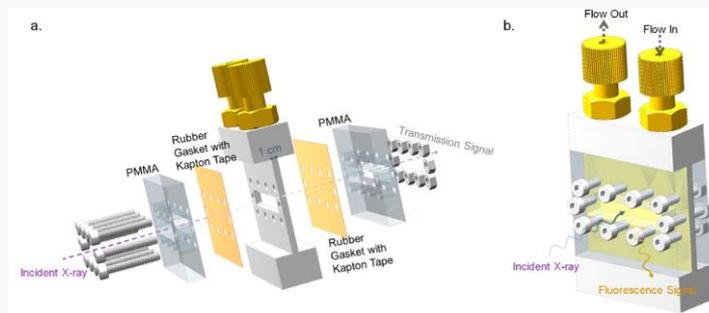
Solid sample holder



In situ catalytic system

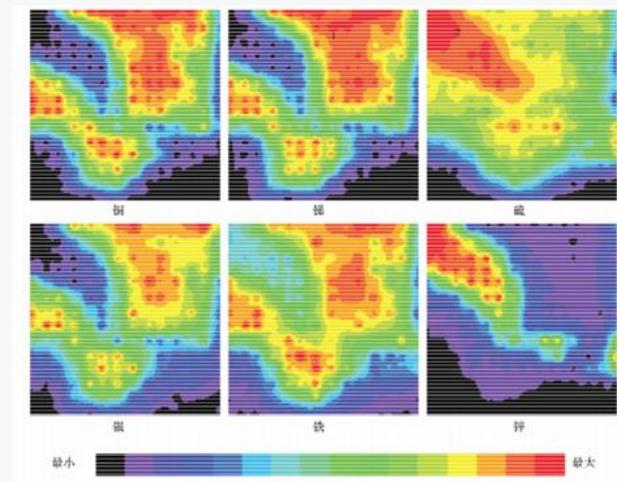
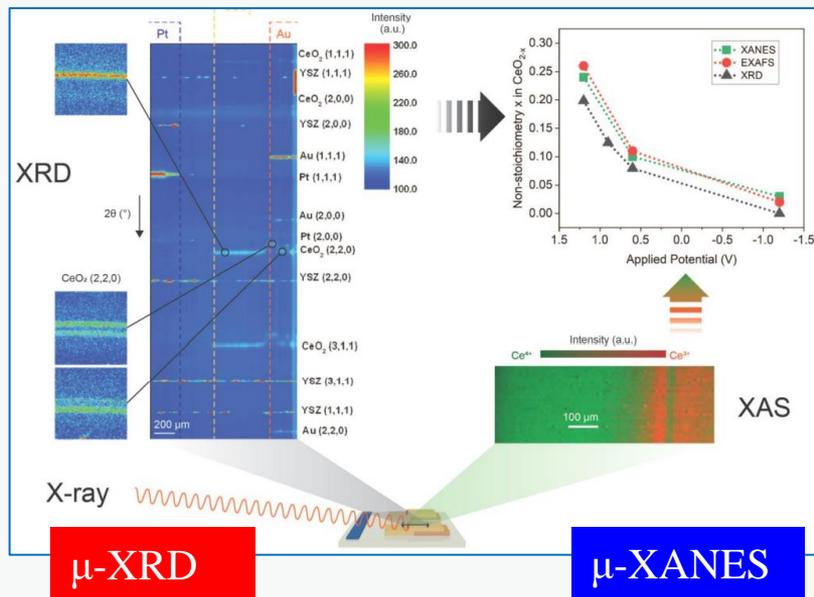


gas cell



7. Unique features

- Obtain the chemical composition, element distribution and crystal structure simultaneously

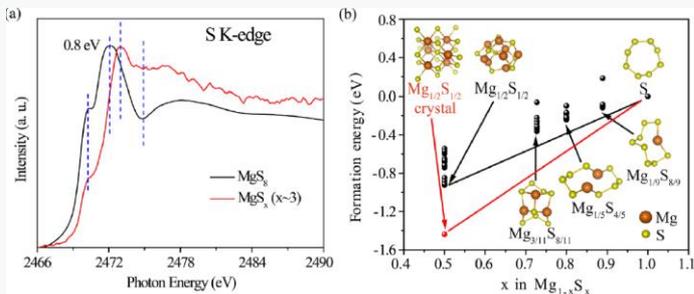


μ -XRF

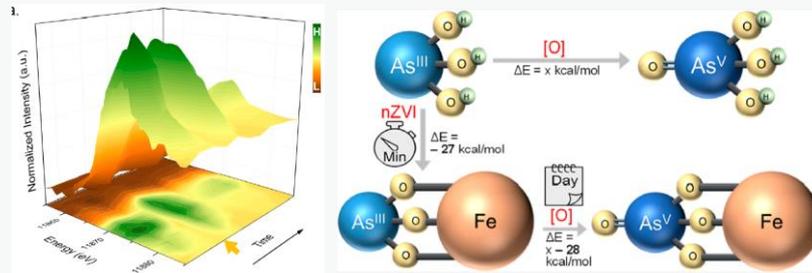
8. Potential applications

valence states, local Structure

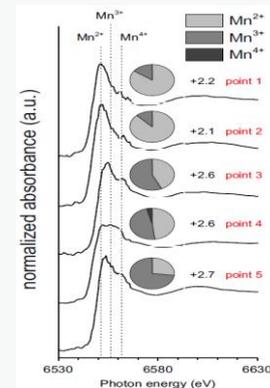
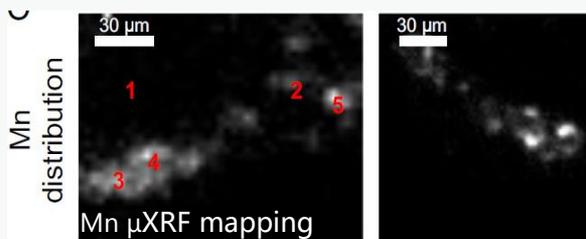
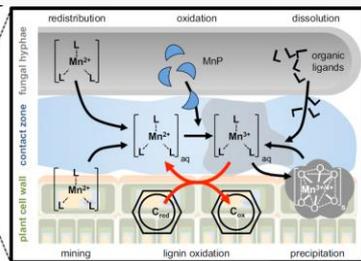
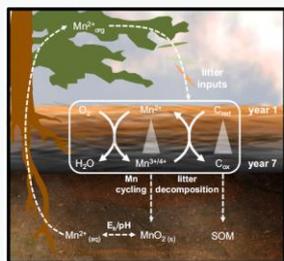
- Investigation of the Capacity Degradation Mechanism in S-containing Batteries



- Trace Key Mechanistic Features of catalysis reaction



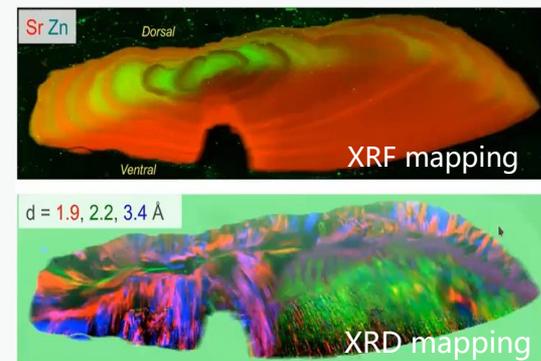
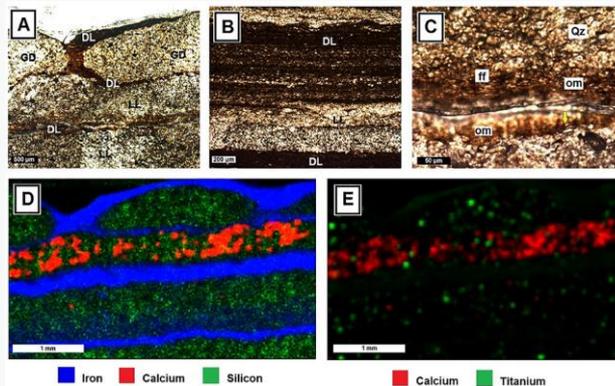
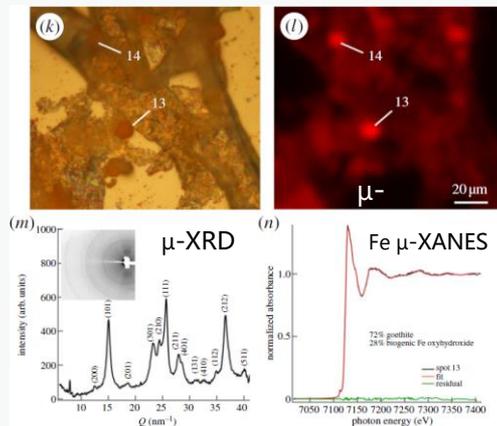
- Long-term litter decomposition controlled by manganese redox cycling in soil



8. Potential applications

chemical composition, elements distribution

- A role for iron and oxygen chemistry in preserving soft tissues, cells and molecules from deep time
- the process of elemental migration associated with marine sediments and sedimentary rocks
- Date and understand the behavior of migratory fish



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环境能源线站

4

High Resolution Hard X-
ray Beamline
高分辨硬X射线谱学线站

➤ High Resolution Hard X-ray Beamline

1. Key features

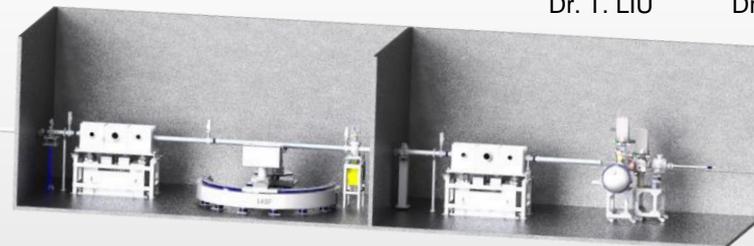
◆ High Energy Resolution



Dr. T. LIU



Dr. H. LI



Light source	Undulator
Energy range (keV)	4.0 – 20.0
Energy resolution	< 500 meV
Flux at 10 keV (ph/s)	$10^{12} \sim 10^{13}$ ph/s
Spot size at sample (μm^2)	$\sim 6.0 \times 3.0$ (EH1) $\sim 2.0 \times 1.0$ (EH2)
Key features	Photon in-Photon out Photon in-Electron out

Method

RIXS, XES

HERFD-XAS

XRS

HAXPES

Application

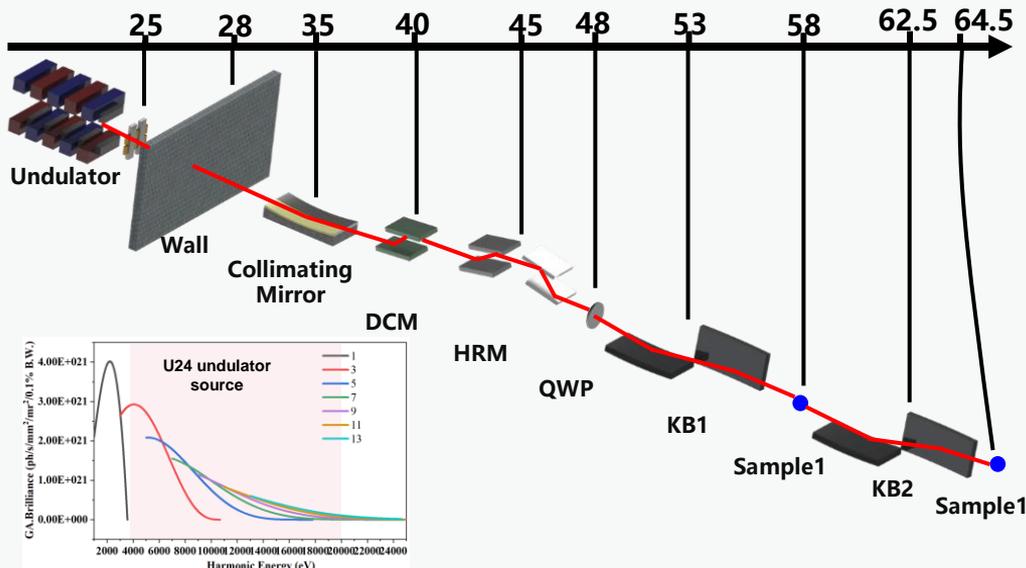
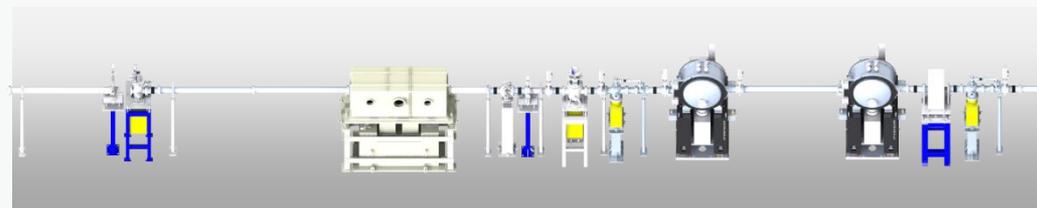
Rare Earth Materials

Magnetic Materials

Semiconductor

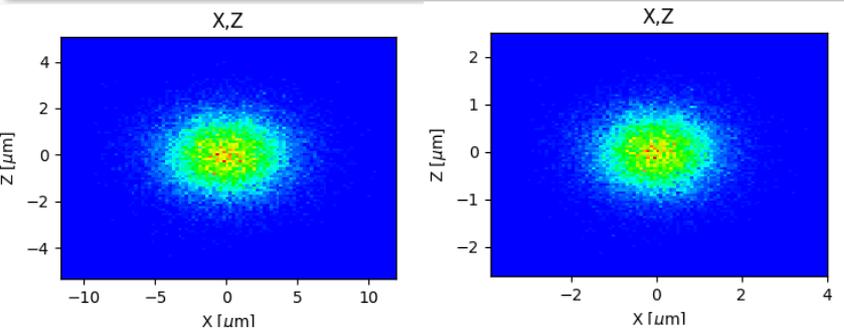
Ferroelectrics, Multiferroics

2. Beamline Optics

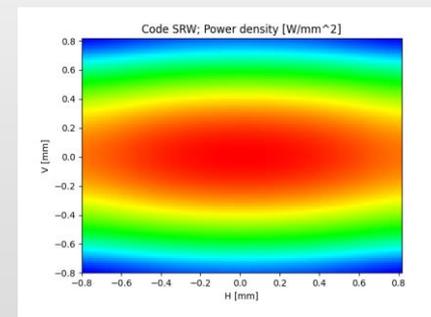
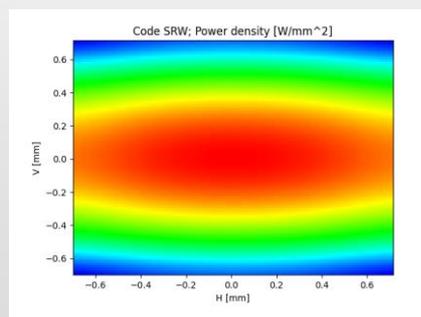
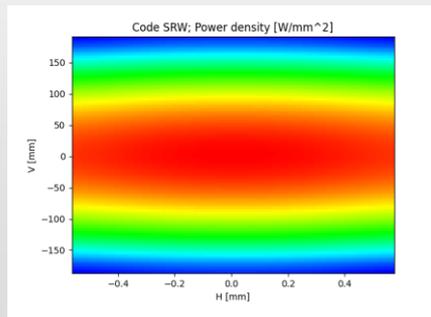


Optics		
Collimating Mirror	Shape	Plane elliptical
Primary Monochromator (DCM)	Type	LN2 cooled Double Crystal
	Energy range	4-20 keV
	Resolving power	< 2 eV
	Available reflections	Si(111), Si(311)
Secondary monochromator (HRM)	Type	Double channel-cut (+ - -)
	Energy range	5-20 keV
	Resolving power	< 150 meV
	Available reflections	Si(400)
Phase retarder	Type	Single stage, Single crystal diamond
Kirkpatrick-Baez Mirror 1	Shape	Cylinder
	Energy range	4-9 keV (Si) 9-20 keV (Rh)
	Usage	Vertical & Horizontal focusing
Kirkpatrick-Baez Mirror 2	Shape	Cylinder
	Energy range	4-9 keV (Si) 9-20 keV (Rh)
	Usage	Vertical & Horizontal focusing

3. X-ray tracing and thermal analyses



Sample Spot	EH1	EH2
Position (m)	58	64.5
Energy (keV)	10	10
Size (μm^2 , FWHM, H \times V)	5.65 \times 2.29	1.73 \times 1.13
Divergence (μrad^2 , FWHM, H \times V)	105.82 \times 45.90	328.81 \times 92.69
Flux (phs/s/0.1% bw)	1.19E+13 (10 keV)	8.77E+12 (10 keV)



OE	Primary Slit	Collimating Mirror	DCM
Absorbed Power (W)	2673.64	12.95	84.50
Power Density (W/mm^2)	48.38	12.40	18.80

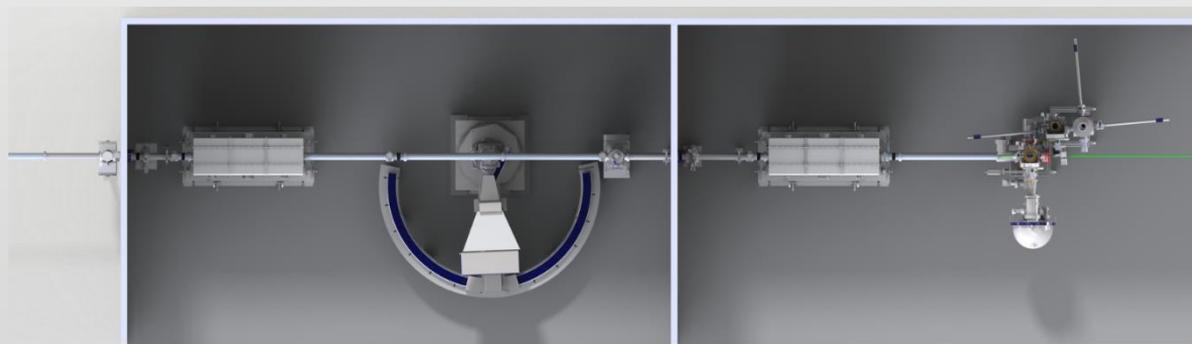
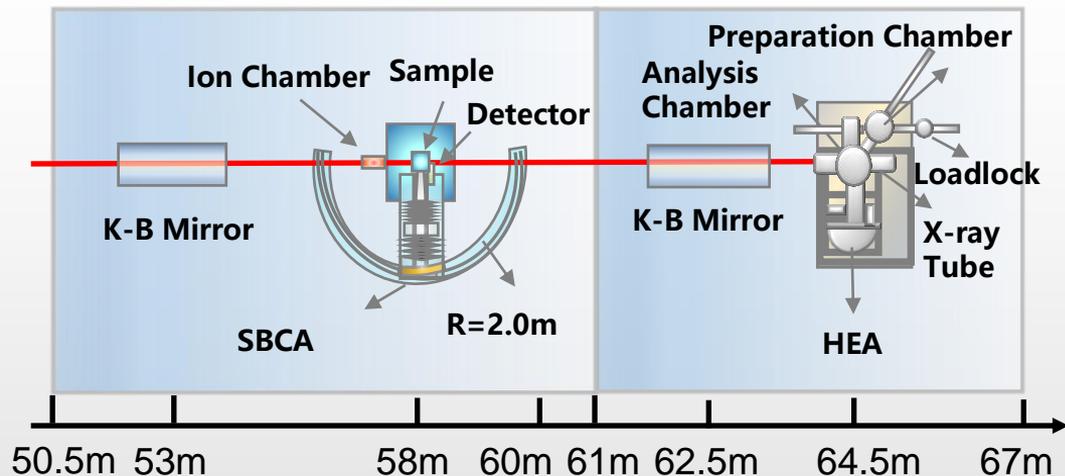
4. Experimental Hutch

EH 1:

- ✓ HARFD-XAS
- ✓ RIXS/XES
- ✓ XRS

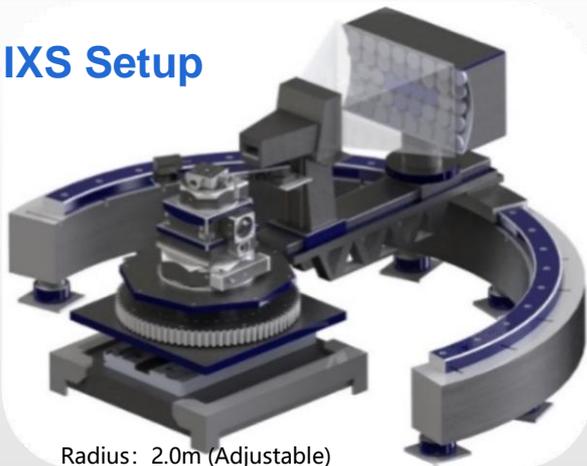
EH 2:

- ✓ HAXPES
- ✓ Off-line HAXPES



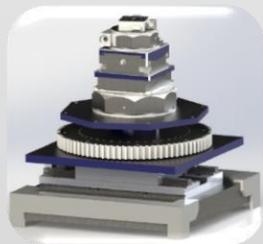
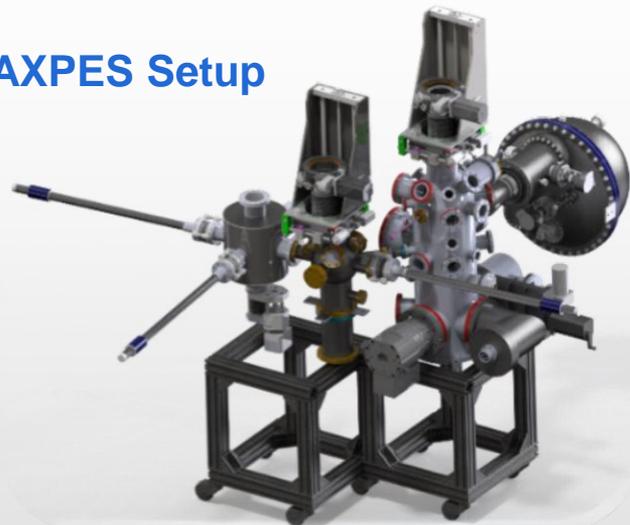
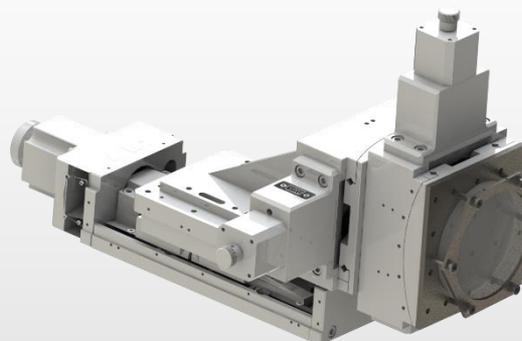
5. Detectors and Instruments

IXS Setup

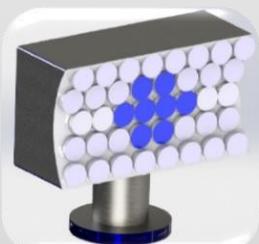


Radius: 2.0m (Adjustable)

HAXPES Setup



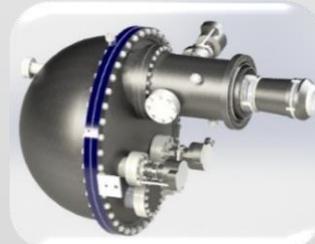
Sample Stage



SBCA



1D&2D Detector



HEA



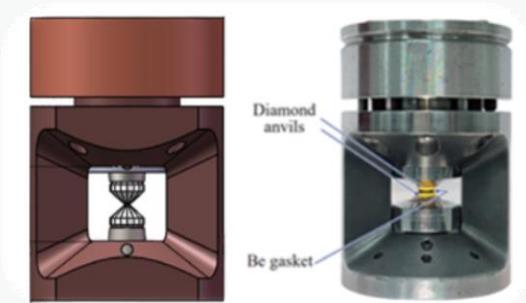
Ion Gun



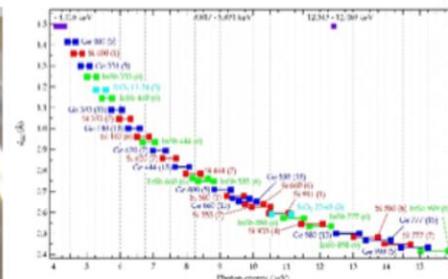
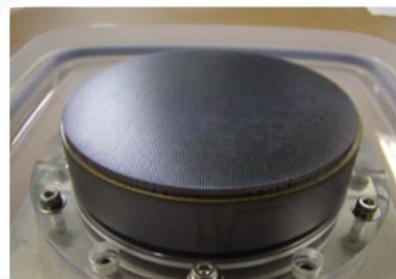
UHV chamber

6. User Facilities

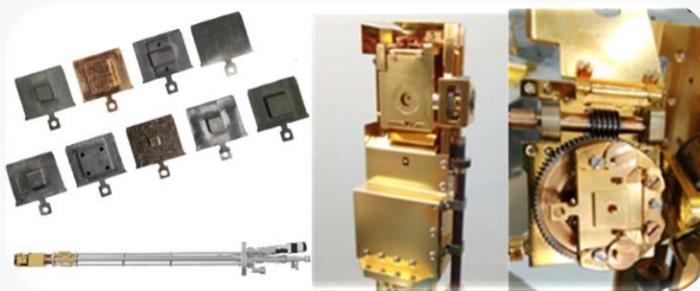
- ❖ This beamline will be equipped with unique sample environments (high dc magnetic fields, low/high temperatures, high pressure).



High Pressure sample holder



Available analysers



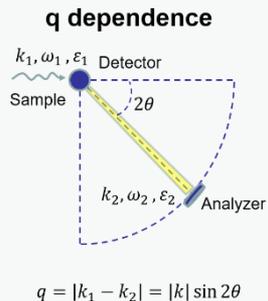
Manipulator head with Flag type sample holder compartment



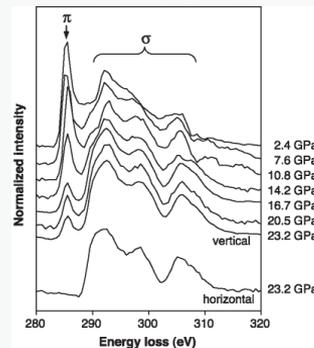
Phase retarder & Magnetic field generator

7. Potential applications

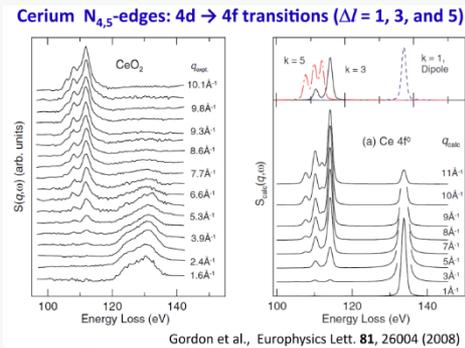
- Focus on the rare earth materials, magnetic materials, geologic materials et al.



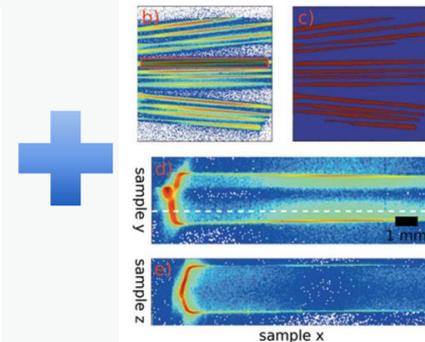
Non-resonant
Inelastic x-ray
Scattering



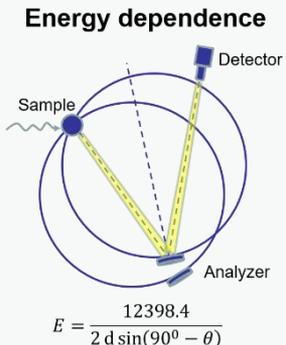
XANES-type XRS, light elements,
High pressure



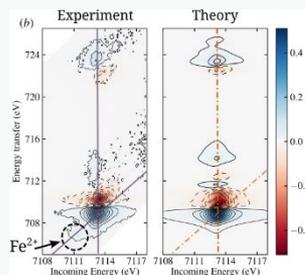
Q-dependence XRS, l -DOS



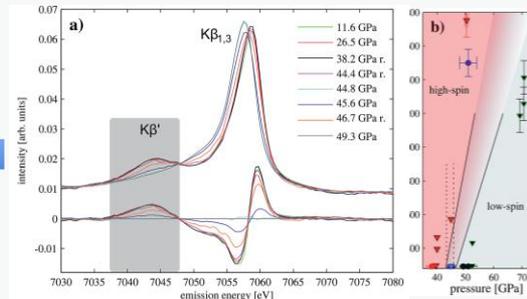
XRS Imaging, Direct tomography with
chemical bond



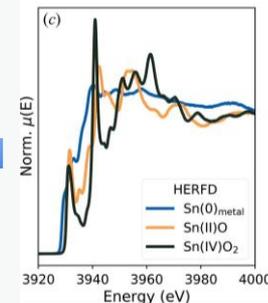
Resonant
Inelastic x-ray
Scattering



RIXS-MCD, Spin in the supermagnetic



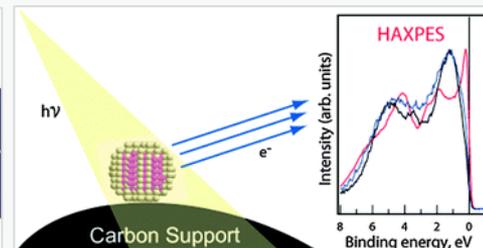
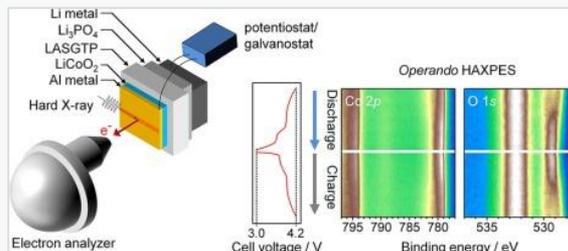
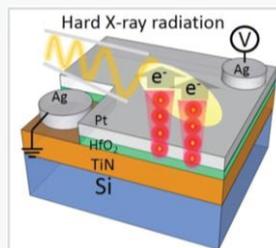
XES-MCD, Spin crossover in the earth materials



HERFD, fine edge structure

7. Potential applications

➤ Industrial application

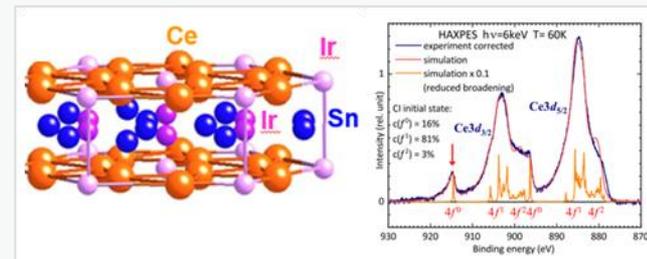
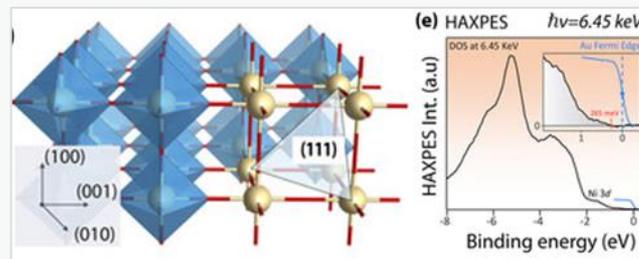


Microelectronics

Battery

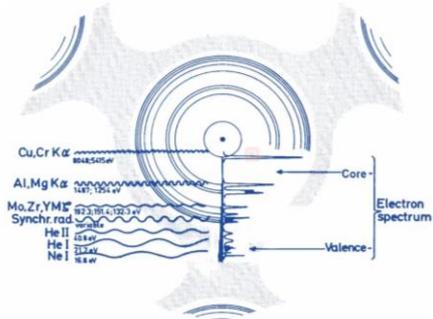
Catalysts

➤ Fundamental research



Strongly-correlated materials

HAXPES :2-12keV



- Probing Depth
- Chemical Analysis
- Electronic Structure
- Magnetic Ordering

Thank you for your attention !

Contacts: Dr. Yang

Email: yangchzh6@mail.sysu.edu.cn

Phone: 13070246505



深圳综合粒子设施研究院
Institute of Advanced Science Facilities, Shenzhen

深圳市光明区新湖街道
圳园路268号A3栋

268 Zhenyuan St, Building A3, Floor 3-6, Guangming District,
Shenzhen, Guangdong, P.R.China

